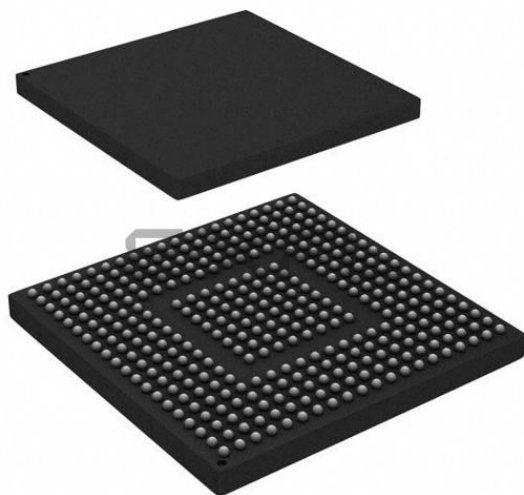




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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

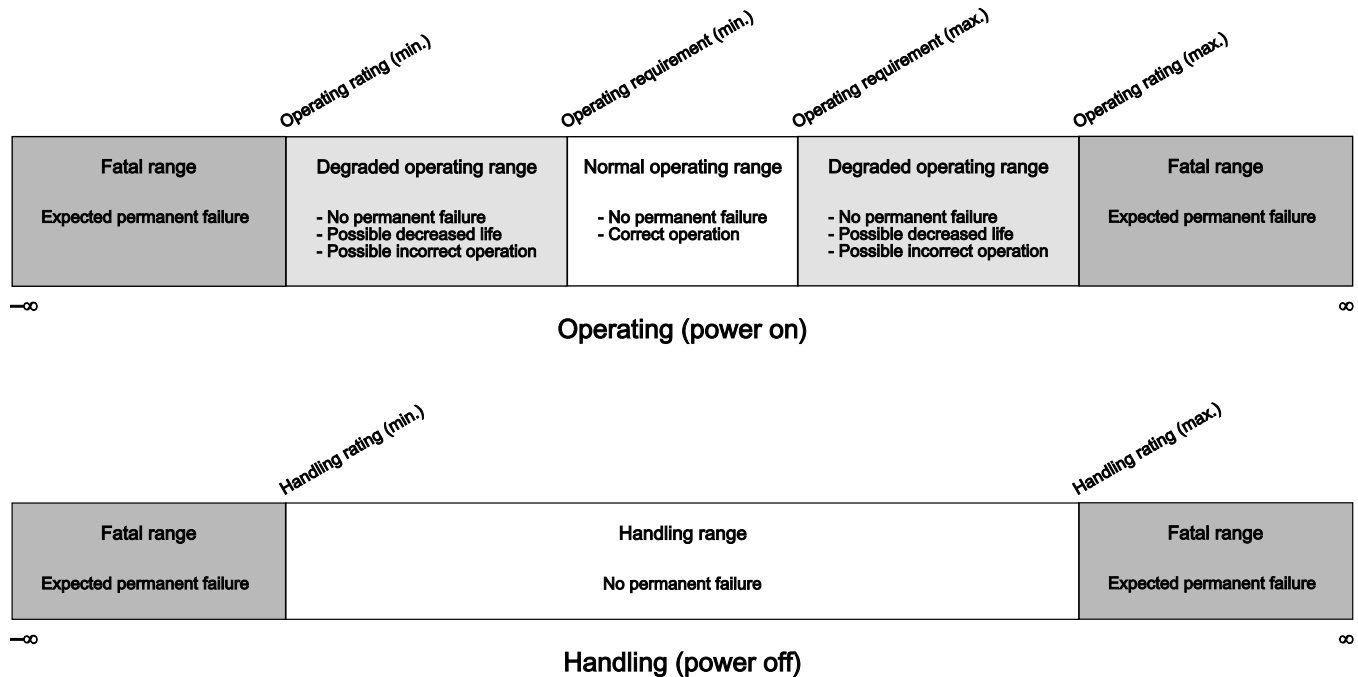
Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Active
Core Processor	ARM® Cortex®-A5
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	500MHz
Co-Processors/DSP	Multimedia; NEON™ MPE
RAM Controllers	LPDDR2, DDR3, DRAM
Graphics Acceleration	Yes
Display & Interface Controllers	DCU, GPU, LCD, VideoADC, VIU
Ethernet	10/100Mbps (2)
SATA	-
USB	USB 2.0 OTG + PHY (1)
Voltage - I/O	3.3V
Operating Temperature	-40°C ~ 85°C (TA)
Security Features	-
Package / Case	364-LFBGA
Supplier Device Package	364-LFBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mvf51nn152cmk50

3.6 Relationship between ratings and operating requirements



3.7 Guidelines for ratings and operating requirements

Follow these guidelines for ratings and operating requirements:

- Never exceed any of the chip's ratings.
- During normal operation, don't exceed any of the chip's operating requirements.
- If you must exceed an operating requirement at times other than during normal operation (for example, during power sequencing), limit the duration as much as possible.

3.8 Definition: Typical value

A *typical value* is a specified value for a technical characteristic that:

- Lies within the range of values specified by the operating behavior
- Given the typical manufacturing process, is representative of that characteristic during operation when you meet the typical-value conditions or other specified conditions

Typical values are provided as design guidelines and are neither tested nor guaranteed.

5 Operating Requirements

5.1 Thermal operating requirements

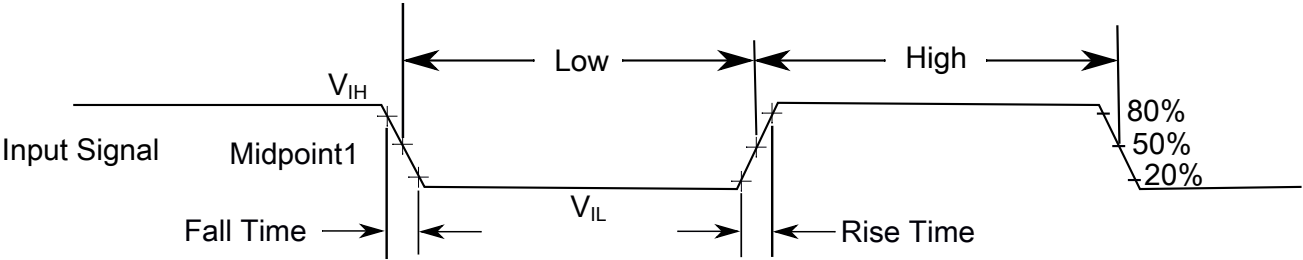
Table 1. Thermal operating requirements

Symbol	Description	Min.	Max.	Unit
T_A	Ambient temperature	-40	85	°C
T_J	Junction temperature		105	°C

6 General

6.1 AC electrical characteristics

Unless otherwise specified, propagation delays are measured from the 50% to the 50% point, and rise and fall times are measured at the 20% and 80% points, as shown in the following figure.



The midpoint is $V_{IL} + (V_{IH} - V_{IL}) / 2$

Figure 2. Input signal measurement reference

2. The Max numbers represent the single worst case value taken from a matrix lot of parts across normal process variation at maximum temperature.
3. CA5, CM4 cores halted
4. 24MHz operation, PLL Bypass
5. 32 kHz /128 kHz operation, PLL Off
6. Lowest power mode with all power retained, RAM retention and LVD protection.
7. Standby Mode. 64K RAM retention. I/O states held. ADCs/DACs optionally power-gated. RTC functional. Wakeup from interrupts. Fast IRC enabled.
8. Standby Mode 16K RAM retention. I/O states held. ADCs/DACs optionally power-gated. RTC functional. Wakeup from interrupts. Fast IRC enabled.
9. All supplies OFF, SRTC, 32kXOSC ON, tampers and monitors ON. 128k IRC optionally ON.

6.2.5 USB PHY current consumption

6.2.5.1 Power Down Mode

Everything powered down, including the VBUS valid detectors, typ condition.

Table 16. USB PHY Current Consumption in Normal Mode

	USBx_VBUS (3.0V) Avg	VDD33_LDOIN (2.5V) Avg	VDD33_LDOIN (1.1V) Avg
Current	5.1 μ A	1.7 μ A	<0.5 μ A

NOTE

The currents on the 2.5 voltage regulator and 3.0 voltage regulator were identified to be the voltage divider circuits in the USB-specific level shifters.

6.2.6 EMC radiated emissions operating behaviors

Table 17. EMC radiated emissions operating behaviors

Symbol	Condition ¹	Clocks	Frequency band ²	Level (Typ) ³	Unit
V _{EME}	Device Configuration, test conditions and EM testing per standard IEC 61967-2; Supply voltages: VDD= 5.0 V VDD33 = 3.3 V VDD15 = 1.5 V VDD12 = 1.2 V Temp = 25°C	FCPU = 396 MHz FBUS = 66 MHz External Crystal = 24 MHz	150 KHz – 50 MHz	22	dB μ V
			50 MHz – 150 MHz	24	
			150 MHz – 500 MHz	25	
			500–1000	20	
			IEC level ⁴	K	—

1. Measurements were made per IEC 61967-2 while the device was running basic application code.
2. Measurements were performed on the BGA364 version of the device

Table 25. DDR3 mode DC Electrical characteristics (continued)

Symbol	Parameter	Test condition	Min	Typ	Max	Unit	Notes
Tri-state I/O supply current ³	lcc-ovdd	V _{in} = ovdd or 0			5		
Tri-state vdd2p5 supply current ³	lcc-vdd2p5	V _i = vddi or 0			1.5		
Tri-state core supply current ³	lcc-vddi				1		
Driver unit (240 Ohm) calibration resolution	Rres				10	Ohm	

1. The single-ended signals need to be within the respective limits (V_{ih}(dc) max, V_{il}(dc) min) for single-ended signals as well as the limitations for overshoot and undershoot.
2. V_{tt} is expected to track ovdd/2.
3. Typ condition: typ model, 1.5 V, and 25 °C. Max condition: bcs model, 1.575V, and -40 °C. Min condition: wcs model, 1.425V, and max T_j °C 125 °C junction

Table 26. LPDDR2 mode AC Electrical characteristics

Symbol	Parameter	Test condition	Min	Max	Unit	Notes
V _{ih} (ac)	AC input logic high		V _{ref} +0.22	ovdd	V	Note that the Jedec LPDDR2 specification (JESD209-2B) supersedes any specification in this document.
V _{il} (ac)	AC input logic low			V _{ref} -0.22	V	
V _{idh} (ac) ¹	AC differential input high voltage		0.44	-	V	
V _{idl} (ac) ¹	AC differential input low voltage			0.44	V	
V _{ix} (ac) ²	AC differential input crosspoint voltage	Relative to ovdd/2	-0.12	0.12	V	
V _{peak}	Over/undershoot peak			0.35	V	
V _{area}	Over/undershoot area (above ovdd or below ovss)	at 800MHz data rate		0.3	V*ns	
t _{sr}	Single output slew rate		0.4	2	V/ns	
t _{skd}	Skew between pad rise/fall asymmetry + skew caused by SSN			0.2	ns	

NOTE

WBREG is the Well Bias Regulator. Supplies PD1 WELL during well bias modes.

8.3 Absolute maximum ratings

NOTE

These are the values above which device can get damaged. Refer to the recommended operating conditions table for intended use case values

Table 29. Absolute maximum ratings

Symbol	Parameters	Min	Max	Unit
USB0_VBUS	VBUS supply for USB	-	5.25	V
USB1_VBUS	VBUS supply for USB	-	5.25	V
USB_DCAP	USB LDO 5V->3.3V Outpu	-0.3	3.6	V
VBAT	Battery supply in case of LDOIN fails	-0.3	3.6	V
VDD33_LDOIN	LDO input supply	-0.3	3.6	V
DECAP_V11_LDO_OUT	LDO 3.3V -> 1.1V Output	-0.3	1.3	V
DECAP_V25_LDO_OUT	LDO 3.3V -> 2.5 Output for PLL, DDR, EFUSE	-0.3	3.6	V
VDD33	GPIO 3.3V IO supply	-0.3	3.6	V
VDDREG	Device PMU regulator and External ballast supply	-0.3	3.6	V
VDDA33_ADC	3.3V supply for ADC, DAC and IO segment	-0.3	3.6	V
VREFH_ADC	3.3V supply of AFE (Video ADC)	-0.3	3.6	V
VDDA33_AFE	3.3V supply of AFE (Video ADC)	-0.3	3.6	V
VDD12_AFE	1.2V supply for AFE (Video ADC)	-0.3	1.3	V
FA_VDD	Test purpose only	-0.3	1.3	V
VDD	1.2V core supply	-0.3	1.3	V
SDRAMC_VDD1P5	1.2/1.5 DDR Main IO supply	-0.3	1.975	V
SDRAMC_VDD2P5	2.5V DDR pre-drive supply DD2P5_LDO_OUT	-0.3	3.6	V

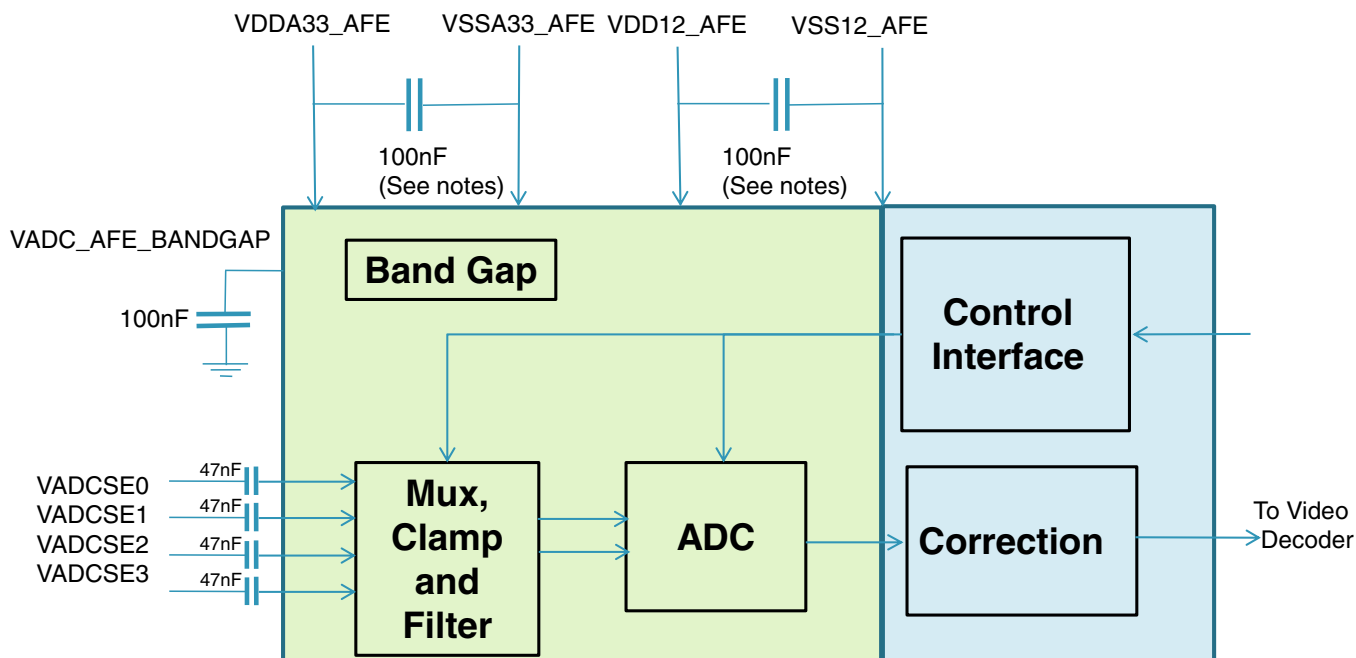
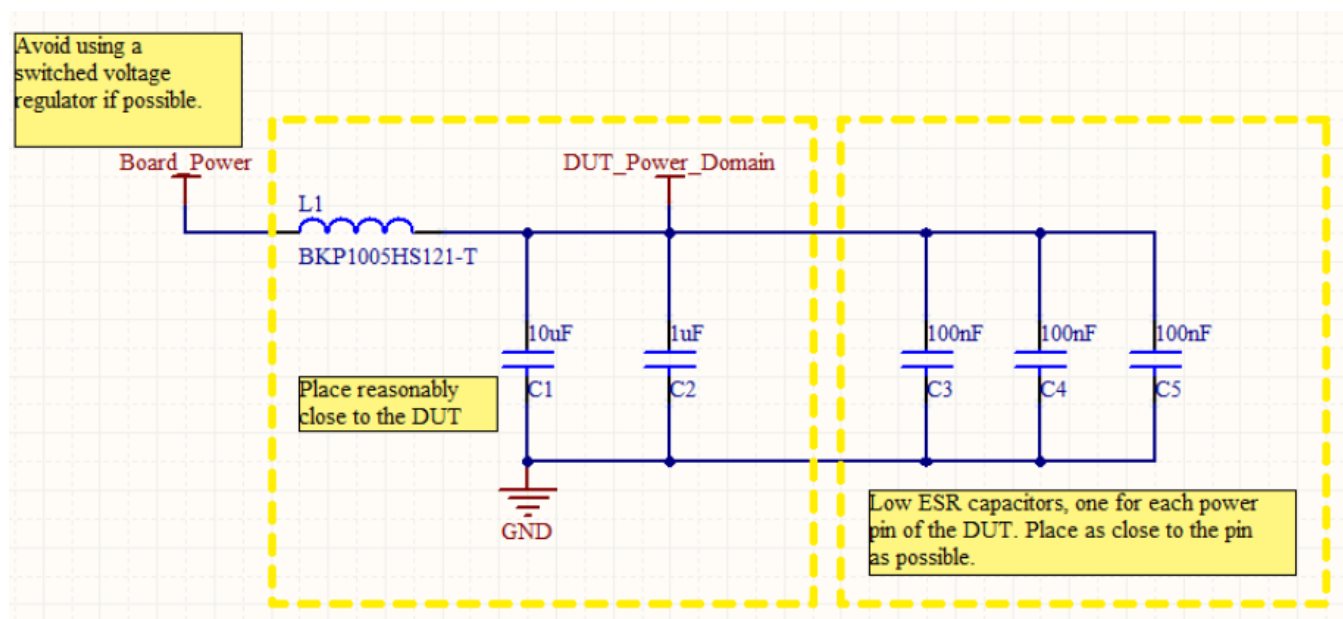
Table 34. 12-bit DAC operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
t_{DACHP}	Full-scale settling time (0x080 to 0xF7F) — high-power mode	—	3	5	μs	1
$t_{CCDACLP}$	Code-to-code settling time (0xBF8 to 0xC08)				μs	1
	low-power mode	—	5	—		
	high-power mode	—	1	—		
$V_{dacoutl}$	DAC output voltage range low — high-speed mode, no load, DAC set to 0x000	—	—	100	mV	
$V_{dacouth}$	DAC output voltage range high — high-speed mode, no load, DAC set to 0xFFF	$V_{DACR} - 100$	—	V_{DACR}	mV	
INL	Integral non-linearity error — high speed mode	—	—	± 8	LSB	2
DNL	Differential non-linearity error — $V_{DACR} = V_{REF_OUT}$	—	—	± 1	LSB	3
V_{OFFSET}	Offset error	—	± 0.4	± 0.8	%FSR	4
E_G	Gain error	—	± 0.1	± 0.6	%FSR	4
PSRR	Power supply rejection ratio, $V_{DDA} = 3\text{ V}$, $T = 25\text{ }^{\circ}\text{C}$		70		dB	
T_{CO}	Temperature coefficient offset voltage	—	3.7	—	$\mu\text{V}/^{\circ}\text{C}$	5
T_{GE}	Temperature coefficient gain error	—	0.000421	—	%FSR/ $^{\circ}\text{C}$	
A_C	Offset aging coefficient	—	—	100	$\mu\text{V}/\text{yr}$	
Rop	Output resistance load = 3 k Ω	—	—	250	Ω	
SR	Slew rate -80h $\rightarrow$ F7Fh $\rightarrow$ 80h				$\text{V}/\mu\text{s}$	
	High power (SP_{HP})		1.7	3		
	Low power (SP_{LP})		0.3	0.6		
CT	Channel to channel cross talk	—	70		dB	

- Settling within ± 1 LSB
- The INL is measured for 0+100mV to $V_{DACR} - 100\text{ mV}$
- The DNL is measured for 0+100mV to $V_{DACR} - 100\text{ mV}$
- Calculated by a best fit curve from $V_{SS} + 100\text{ mV}$ to $V_{DACR} - 100\text{ mV}$
- $V_{DDA} = 3.0\text{ V}$, reference select set for V_{DDA} ($DACx_CO:DACRFS = 1$), high power mode ($DACx_CO:LPEN = 0$), DAC set to 0x800, Temp range from $-40\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$

Table 35. VideoADC Specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V _{BG}	Bandgap voltage	—	0.6	—	V	Bandgap voltage on VADC_AFE_BANDGAP pin. Pin should be decoupled with a 100nF capacitor


Figure 12. VideoADC supply scheme

Figure 13. VideoADC supply decoupling

9.5.4.2 DDR3 Read Cycle

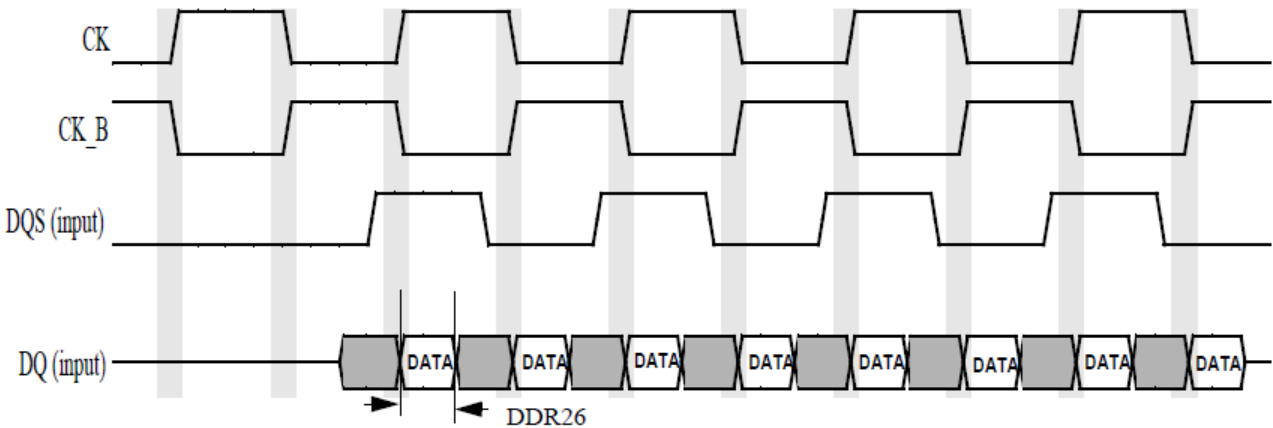


Figure 42. DDR3 Read Cycle

Table 55. DDR3 Read Cycle

ID	Parameter	Symbol	CK = 400 MHz		Unit
			Min	Max	
DDR26	Minimum required DQ valid window width	-	750	-	ps

NOTE

To receive the reported setup and hold values, read calibration should be performed in order to locate the DQS in the middle of DQ window.

NOTE

All measurements are in reference to Vref level.

NOTE

Measurements were done using balanced load and 25 ohms resistor from outputs to VDD_REF

9.6 Communication interfaces

9.6.1 DSPI timing specifications

Table 60. DSPI timing

No.	Symbol	Characteristic	Condition	Min	Max	Unit
1	t_{SCK}	SCK Cycle Time	—	$t_{SYS} * 2$	—	ns
4	t_{SDC}	SCK Clock Pulse Width	—	40%	60%	t_{SCK}
2	t_{CSC}	CS to SCK Delay	Master	16	—	ns
3	t_{ASC}	After SCK Delay	Master	16	—	ns
5	t_A	Slave Access Time (SS active to SOUT driven)	Slave	—	15	ns
6	t_{DI}	Slave Disable Time (SS inactive to SOUT High-Z or invalid)	Slave	—	10	ns
9	t_{SUI}	Data Setup Time for Inputs	Master	9	—	ns
			Slave	4	—	
10	t_{HI}	Data Hold Time for Inputs	Master	0	—	ns
			Slave	2	—	
11	t_{DV}	Data Valid (after SCK edge) for Outputs	Master	—	5	ns
			Slave	—	10	
12	t_{HO}	Data Hold Time for Outputs	Master	0	—	ns
			Slave	0	—	

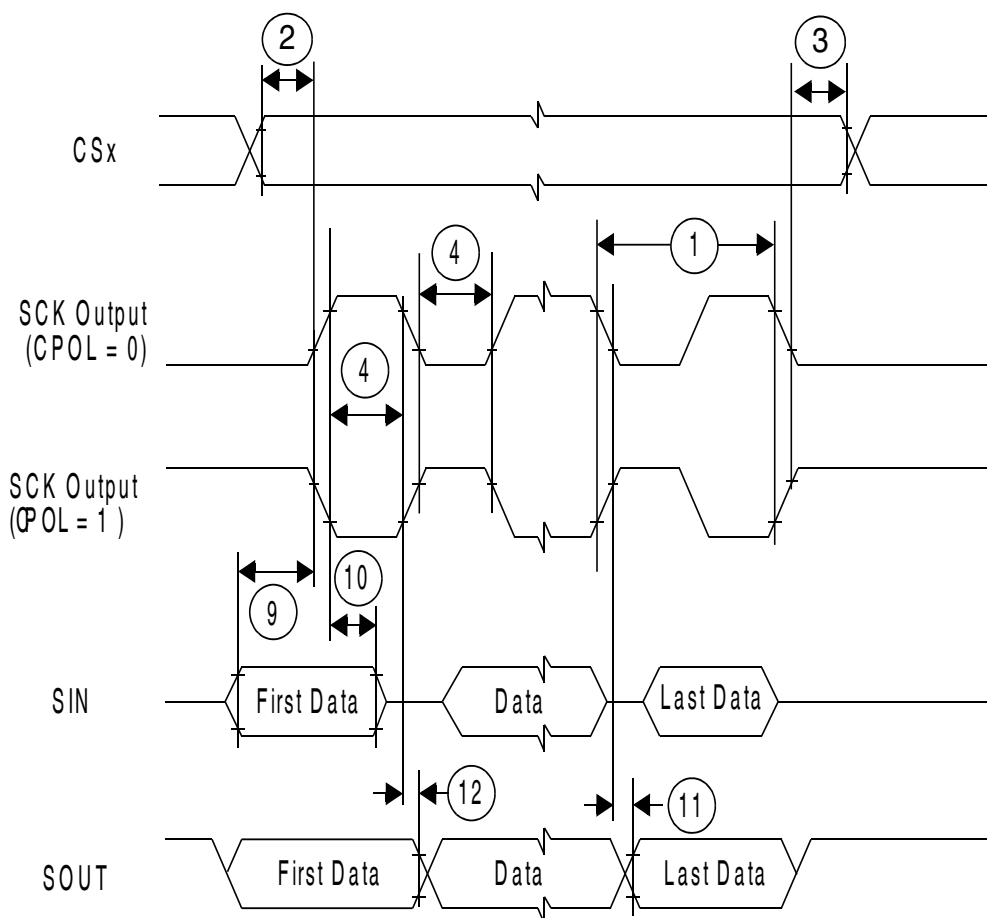


Figure 47. DSPI classic SPI timing master, CPHA=0

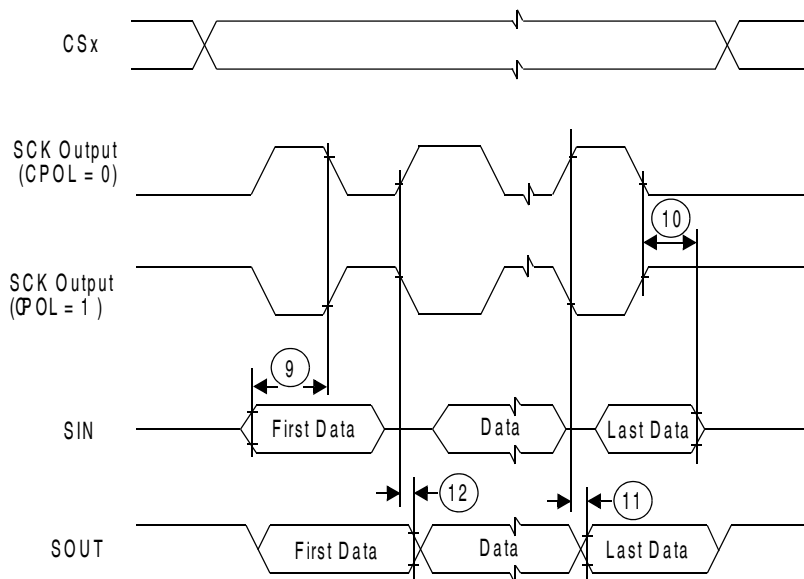


Figure 48. DSPI classic SPI timing master, CPHA=1

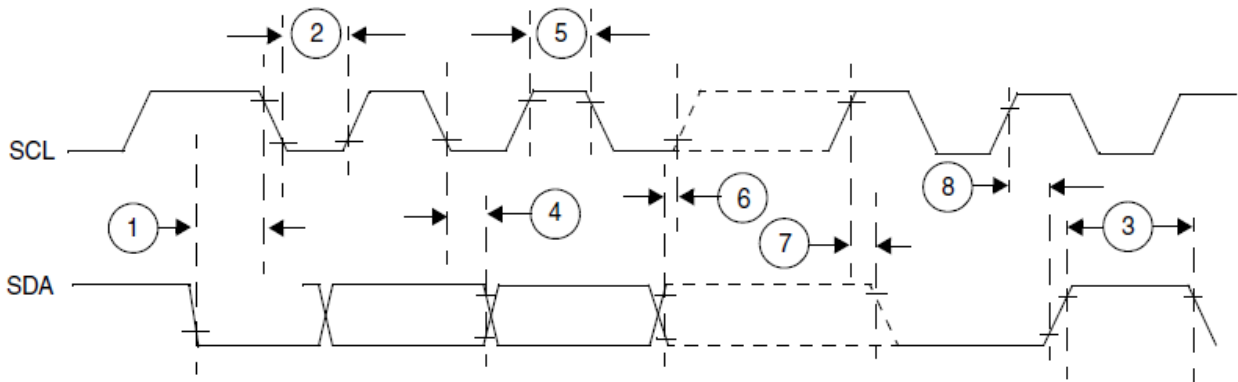


Figure 51. I2C input/output timing

9.6.3 SDHC specifications

The following timing specs are defined at the chip I/O pin and must be translated appropriately to arrive at timing specs/constraints for the physical interface. A load of 50 pF is assumed.

Table 63. SDHC switching specifications

Num	Symbol	Description	Min.	Max.	Unit
		Operating voltage	1.71	3.6	V
		Card input clock			
SD1	fpp	Clock frequency (low speed)	0	400	kHz
	fpp	Clock frequency (SD\SDIO full speed\high speed)	0	25\50	MHz
	fpp	Clock frequency (MMC full speed\high speed)	0	20\50	MHz
	f _{OD}	Clock frequency (identification mode)	0	400	kHz
SD2	t _{WL}	Clock low time	7	—	ns
SD3	t _{WH}	Clock high time	7	—	ns
SD4	t _{TLH}	Clock rise time	—	3	ns
SD5	t _{THL}	Clock fall time	—	3	ns
		SDHC output / card inputs SDHC_CMD, SDHC_DAT (reference to SDHC_CLK)			
SD6	t _{OD}	SDHC output delay (output valid)	-5	4	ns
		SDHC input / card inputs SDHC_CMD, SDHC_DAT (reference to SDHC_CLK)			
SD7	t _{ISU}	SDHC input setup time	5	—	ns
SD8	t _{IH}	SDHC input hold time	0	—	ns

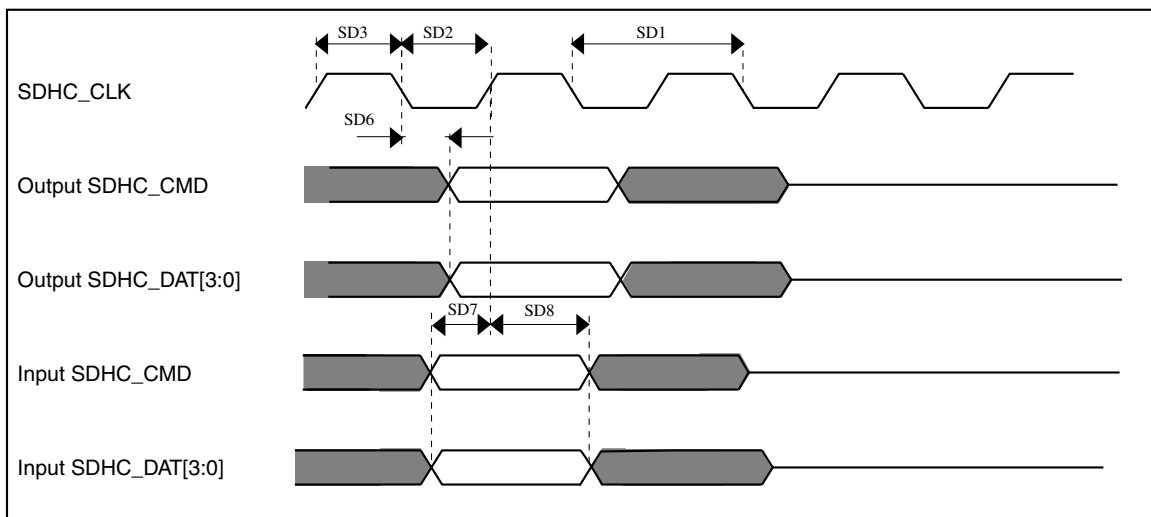


Figure 52. SDHC timing

9.6.4 USB PHY specifications

This section describes the USB-OTG PHY and the USB Host port PHY parameters.

The USB PHY meets the electrical compliance requirements defined in the Universal Serial Bus Revision 2.0 OTG, USB Host with the amendments below (On-The-Go and Embedded Host Supplement to the USB Revision 2.0 Specification is not applicable to Host port).

- USB ENGINEERING CHANGE NOTICE
 - Title: 5V Short Circuit Withstand Requirement Change
 - Applies to: Universal Serial Bus Specification, Revision 2.0
- Errata for USB Revision 2.0 April 27, 2000 as of 12/7/2000
- USB ENGINEERING CHANGE NOTICE
 - Title: Pull-up/Pull-down resistors
 - Applies to: Universal Serial Bus Specification, Revision 2.0
- USB ENGINEERING CHANGE NOTICE
 - Title: Suspend Current Limit Changes
 - Applies to: Universal Serial Bus Specification, Revision 2.0
- On-The-Go and Embedded Host Supplement to the USB Revision 2.0 Specification
 - Revision 2.0 plus errata and ecn June 4, 2010
- Battery Charging Specification (available from USB-IF)
 - Revision 1.2, December 7, 2010

9.7.9 PLL6 (Video PLL) Electrical Parameters

Table 72. PLL6 Electrical Parameters

Parameter	Value
Clock output range	650 MHz ~1.3 GHz
Reference clock	24 MHz
Lock time	<7500 reference cycles
Long term jitter(RMS) ¹	<42ps @ 1128 MHz
Period jitter(p2p)	<130ps @960MHz
Duty Cycle	43%~57%

1. Jitter numbers are measured at divided PLL clock because high frequency cannot be brought-out on IO pad & at use case frequency.

9.8 Debug specifications

9.8.1 JTAG electricals

Table 73. JTAG limited voltage range electricals

Symbol	Description	Min.	Max.	Unit
	Operating voltage	2.7	3.6	V
J1	TCLK frequency of operation - Boundary Scan - JTAG and CJTAG - Serial Wire Debug	- - -	25 25 25	MHz
J2	TCLK cycle period	1/J1	—	ns
J3	TCLK clock pulse width - Boundary Scan - JTAG and CJTAG - Serial Wire Debug	20 20 20	— — —	ns ns ns
J4	TCLK rise and fall times	Refer Table 21		ns
J5	Boundary scan input data setup time to TCLK rise	8	—	ns
J6	Boundary scan input data hold time after TCLK rise	1.3	—	ns
J7	TCLK low to boundary scan output data valid	—	17	ns
J8	TCLK low to boundary scan output high-Z	—	17	ns
J9	TMS, TDI input data setup time to TCLK rise	8	—	ns
J10	TMS, TDI input data hold time after TCLK rise	1.3	—	ns
J11	TCLK low to TDO data valid	—	17	ns
J12	TCLK low to TDO high-Z	—	17	ns

364 MAP BGA	176 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
A10	—	DDR_A[13]			DDR_A13							
C10	—	DDR_A[12]			DDR_A12							
D10	—	DDR_A[11]			DDR_A11							
D7	—	DDR_A[10]			DDR_A10							
B9	—	DDR_A[9]			DDR_A9							
A11	—	DDR_A[8]			DDR_A8							
A7	—	DDR_A[7]			DDR_A7							
A9	—	DDR_A[6]			DDR_A6							
B6	—	DDR_A[5]			DDR_A5							
A6	—	DDR_A[4]			DDR_A4							
B7	—	DDR_A[3]			DDR_A3							
A8	—	DDR_A[2]			DDR_A2							
C11	—	DDR_A[1]			DDR_A1							
C7	—	DDR_A[0]			DDR_A0							
D8	—	DDR_BA[2]			DDR_BA2							
C9	—	DDR_BA[1]			DDR_BA1							
C8	—	DDR_BA[0]			DDR_BA0							
B4	—	DDR_CAS_b			DDR_CAS_b							
A5	—	DDR_CKE[0]			DDR_CKE0							
A2	—	DDR_CLK[0]			DDR_CLK0							
B2	—	DDR_CLK_b[0]			DDR_CLK_b0							
C5	—	DDR_CS_b[0]			DDR_CS_b0							
D2	—	DDR_D[15]			DDR_D15							
H2	—	DDR_D[14]			DDR_D14							
C1	—	DDR_D[13]			DDR_D13							
G1	—	DDR_D[12]			DDR_D12							
E2	—	DDR_D[11]			DDR_D11							
H1	—	DDR_D[10]			DDR_D10							
D1	—	DDR_D[9]			DDR_D9							
J1	—	DDR_D[8]			DDR_D8							
G3	—	DDR_D[7]			DDR_D7							
C3	—	DDR_D[6]			DDR_D6							
J3	—	DDR_D[5]			DDR_D5							
F3	—	DDR_D[4]			DDR_D4							
G4	—	DDR_D[3]			DDR_D3							
D4	—	DDR_D[2]			DDR_D2							
H3	—	DDR_D[1]			DDR_D1							
F4	—	DDR_D[0]			DDR_D0							
G2	—	DDR_DQM[1]			DDR_DQM1							

Pinouts

364 MAP BGA	176 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
J4	—	DDR_DQM[0]			DDR_DQM0							
E1	—	DDR_DQS[1]			DDR_DQS1							
D3	—	DDR_DQS[0]			DDR_DQS0							
F1	—	DDR_DQS_b[1]			DDR_DQS_b1							
E3	—	DDR_DQS_b[0]			DDR_DQS_b0							
A4	—	DDR_RAS_b			DDR_RAS_b							
C6	—	DDR_WE_b			DDR_WE_b							
C4	—	DDR_ODT[0]			DDR_ODT0							
B1	—	DDR_ODT[1]			DDR_ODT1							
G5	—	DDR_VREF			DDR_VREF							
A3	—	DDR_ZQ			DDR_ZQ							
D6	—	DDR_RESET			DDR_RESET							
J20	—	PTD31		PTD31	FB_AD31	NF_IO15		FTM3_CH0	SPI2_PCS1			
H20	—	PTD30		PTD30	FB_AD30	NF_IO14		FTM3_CH1	SPI2_PCS0			
H18	—	PTD29		PTD29	FB_AD29	NF_IO13		FTM3_CH2	SPI2_SIN			
H17	—	PTD28		PTD28	FB_AD28	NF_IO12	I2C2_SCL	FTM3_CH3	SPI2_SOUT			
H16	—	PTD27		PTD27	FB_AD27	NF_IO11	I2C2_SDA	FTM3_CH4	SPI2_SCK			
G16	—	PTD26		PTD26	FB_AD26	NF_IO10		FTM3_CH5	SDHC1_WP			
G18	—	PTD25		PTD25	FB_AD25	NF_IO9		FTM3_CH6				
G19	—	PTD24		PTD24	FB_AD24	NF_IO8		FTM3_CH7				
G20	124	PTD23		PTD23/ MII0_ RXDATA[3]	FB_AD23	NF_IO7	FTM2CH0	ENET0_1588_TMR0	SDHC0_DAT4	SCI2_TX	DCU1_R3	
F20	126	PTD22		PTD22/ MII0_ RXDATA[2]	FB_AD22	NF_IO6	FTM2CH1	ENET0_1588_TMR1	SDHC0_DAT5	SCI2_RX	DCU1_R4	
F19	128	PTD21		PTD21/ MII0_CRS	FB_AD21	NF_IO5		ENET0_1588_TMR2	SDHC0_DAT6	SCI2_RTS	DCU1_R5	
F17	129	PTD20		PTD20/ MII0_COL	FB_AD20	NF_IO4		ENET0_1588_TMR3	SDHC0_DAT7	SCI2_CTS	DCU1_R0	
F16	130	PTD19		PTD19	FB_AD19	NF_IO3	ESAI_SCKR	I2C0_SCL	FTM2_QD_PHA	MII0_TXDATA[3]	DCU1_R1	
E18	131	PTD18		PTD18	FB_AD18	NF_IO2	ESAI_FSR	I2C0_SDA	FTM2_QD_PHB	MII0_TXDATA[2]	DCU1_G0	
E20	132	PTD17		PTD17	FB_AD17	NF_IO1	ESAI_HCKR	I2C1_SCL		MII0_TXERR	DCU1_G1	
D20	133	PTD16		PTD16	FB_AD16	NF_IO0	ESAI_HCKT	I2C1_SDA			DCU1_G2	
Y17	86	PTD0		PTD0	QSPI0_A_SCK	SCI2_TX		FB_AD15	SPDIF_EXTCLK			
Y18	87	PTD1		PTD1	QSPI0_A_CS0	SCI2_RX		FB_AD14	SPDIF_IN1			
V18	88	PTD2		PTD2	QSPI0_A_DATA3	SCI2_RTS	SPI1_PCS3	FB_AD13	SPDIF_OUT1			

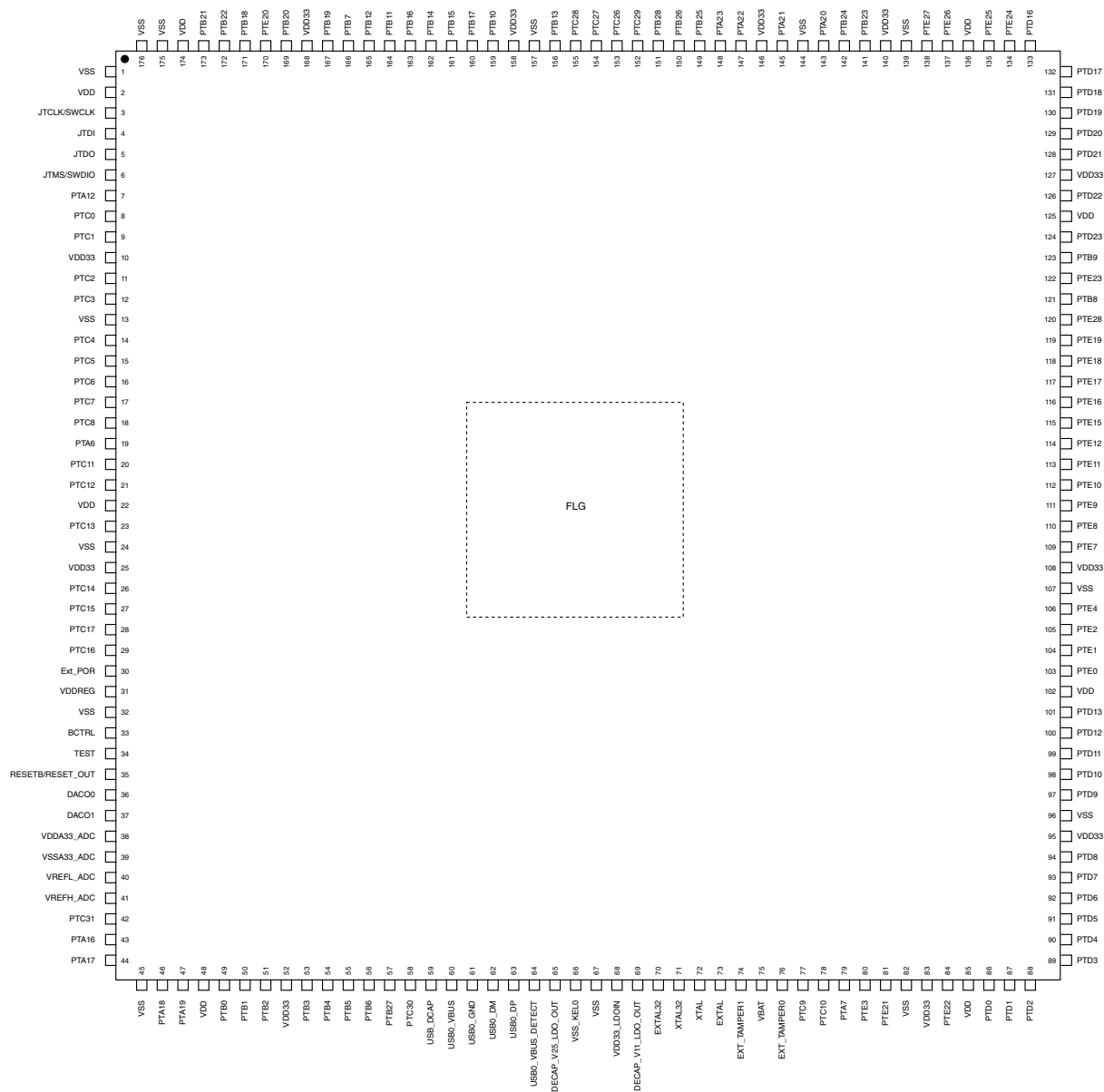


Figure 58. 176 LQFP Pinout Diagram

13 Power Supply Pins

13.1 Power Supply Pins

Table 77. Power Supply Pins

Supply Rail Name	364 MAP BGA	176 LQFP (F-series ONLY)	Comment
DECAP_V11_LDO_OUT	V12	69	On-chip 1.1V LDO output
DECAP_V25_LDO_OUT	T11	65	On-chip 2.5V LDO output (Intended to supply DRAM IO when required)
FA_VDD	N7	—	Factory Use Only (Connect to VDD, internally bonded in LQFP)
SDRAMC_VDD1P5	D5, D11, E4, E7, E9, F5, H5, K5	DRAM not supported in LQFP	1.5V DDR3 DRAM Supply (1.2V for LPDDR2)
SDRAMC_VDD2P5	E6, E10, J5	DRAM not supported in LQFP	2.5V DRAM Supply
USB_DCAP	Y10	59	On-chip 3V LDO output (Intended to be fed by external USB VBUS supply)
USB0_GND	V10	61	
USB1_GND	Y9	USB1 not supported in LQFP	
VADC_AFE_BANDGAP	U5	Video ADC not supported in LQFP	Video ADC Bandgap Output
VBAT	V14	75	On-chip SNVS regulator battery back-up supply option
VDD	G7, G9, G11, G13, H8, H10, H12, H14, J7, J13, K8, K14, L7, L13, M8, M14, N9, N11, N13, P8, P10, P12, P14	2, 22, 48, 85, 102, 125, 136, 174	1.2V Core Supply (Internally Regulated)
VDD33	C12, C15, C18, F18, K3, K17, N3, N17, T17, U16, V8, W18	10, 25, 52, 83, 95, 108, 127, 140, 146, 158, 168	3.3V IO Supply
VDDA33_ADC	V1	38	3.3V Analog To Digital convertor supply
VDD12_AFE	T5	Video ADC not supported in LQFP	1.2V Analog Front End supply for Video ADC
VDDA33_AFE	V3	Video ADC not supported in LQFP	3.3V Analog Front End supply for Video ADC
VDD33_LDOIN	T12	68	On-chip 2.5V LDO, 1.1V LDO and SNVS regulators input supply
VDDREG	P5	31	On-chip HPREG, LPREG, WBREG and ULPREG regulators input supply
VREFH_ADC	W1	41	ATD High Voltage Reference
VREFL_ADC	U3	40	ATD Low Voltage Reference

Table continues on the next page...

**Table 78. Functional Assignment Pins
(continued)**

Signal Name	364 MAP BGA	176 LQFP (F-series ONLY)	Power Group	Pad Type	Default Mode (Reset)	Default Function	Input/Output	Value
PTA31	P16	—	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB0	T6	49	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB1	T7	50	VDD33	GPIO	ALT3	RCON30	Input	Disabled
PTB2	V7	51	VDD33	GPIO	ALT3	RCON31	Input	Disabled
PTB3	W7	53	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB4	Y7	54	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB5	Y8	55	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB6	W8	56	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB7	D13	166	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB8	J16	121	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB9	J19	123	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB10	B15	159	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB11	D14	164	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB12	E13	165	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB13	D15	156	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB14	B14	162	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB15	A14	161	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB16	C14	163	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB17	A15	160	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB18	B12	171	VDD33	GPIO	ALT0	GPIO	Input	Disabled
PTB19	C13	167	VDD33	GPIO	ALT0	GPIO	Input	Disabled
PTB20	A13	169	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB21	E12	173	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB22	D12	172	VDD33	GPIO	ALT0	GPIO	Disabled	
PTB23	A19	141	VDD33	GPIO	ALT3	GPIO	Disabled	
PTB24	A18	142	VDD33	GPIO	ALT3	GPIO	Disabled	
PTB25	B17	149	VDD33	GPIO	ALT3	GPIO	Disabled	
PTB26	A17	150	VDD33	GPIO	ALT3	RCON21	Input	Disabled
PTB27	U8	57	VDD33	GPIO	ALT3	RCON22	Input	Disabled
PTB28	A16	151	VDD33	GPIO	ALT3	RCON23	Input	Disabled
PTC0	L4	8	VDD33	GPIO	ALT7	RCON18	Input	Disabled
PTC1	L5	9	VDD33	GPIO	ALT7	RCON19	Input	Disabled
PTC2	M5	11	VDD33	GPIO	ALT7	RCON20	Input	Disabled
PTC3	M3	12	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC4	L2	14	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC5	M1	15	VDD33	GPIO	ALT0	GPIO	Disabled	
PTC6	N1	16	VDD33	GPIO	ALT0	GPIO	Disabled	

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Table 79. Revision History (continued)

Rev. No.	Date	Substantial Changes
Rev3	04/2012	Updated device name throughout the document Minor editorial updates in the feature list Updated VREG electrical specifications Updated LDO electrical specifications Updated Power consumption operating behaviors table Added USB PHY Current Consumption table Updated GPIO parameters Updated DDR parameters Updated Power sequencing Updated Power supply figure Updated Recommended operating conditions table Removed Reset specifications Updated 12-bit DAC operating requirements Added a note in 12-bit ADC operating conditions section Updated VideoADC Specifications table Updated LCD driver specifications table QuadSPI timing- Replaced VDDE with VDD33 Added notes in DDR3 Timing Parameters and LPDD2 Timing Parameters sections. Updated 24MHz external oscillator electrical characteristics table Updated OSC32K Main Characteristics table Updated Freescale Document Number for 144-pin LQFP Changed pin-name from EXT_POR to TEST2 Updated Pinouts section Updated GPIO Mapping
Rev4	08/2012	Updated Part identification Editorial changes in USB PHY Current Consumption in Normal Mode, GPIO AC Electrical Characteristics (3.3V power mode) Updated Power sequencing table

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